

STN3PF06 P-CHANNEL 60V - 0.18Ω - 3A SOT-223 STripFET™ II POWER MOSFET

Table 1: General Features

TYPE	V_{DSS}	R _{DS(on)}	ID
STN3PF06	60 V	< 0.20 Ω	2.5 A

- TYPICAL R_{DS}(on) = 0.18 Ω
- EXCEPTIONAL dv/dt CAPABILITY
- 100% AVALANCHE TESTED

DESCRIPTION

This Power MOSFET is the latest development of STMicroelectronis unique "Single Feature Size™" strip-based process. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and critical alignment steps therefore a less remarkable manufacturing reproducibility

APPLICATIONS

- DC-DC & DC-AC CONVERTERS
- DC MOTOR CONTROL (DISK DRIVES, etc.)

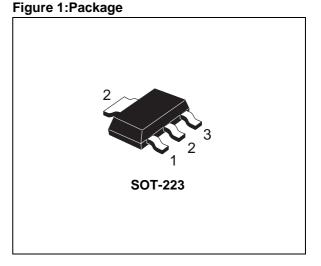


Figure 2: Internal Schematic Diagram

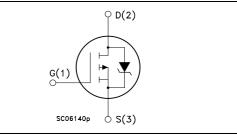


Table 2: Order Codes

SALES TYPE	MARKING	PACKAGE	PACKAGING
STN3PF06	N3PF06	SOT-223	TAPE REEL

Table 3: ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	60	V
V _{DGR}	Drain-gate Voltage ($R_{GS} = 20 \text{ k}\Omega$)	60	V
V _{GS}	Gate- source Voltage	± 20	V
I _D	Drain Current (continuous) at T _C = 25°C	2.5	A
ID	Drain Current (continuous) at T _C = 100°C	1.5	A
I _{DM} (●)	Drain Current (pulsed)	10	A
P _{tot}	Total Dissipation at $T_C = 25^{\circ}C$	2.5	W
	Derating Factor	0.02	W/°C
dv/dt (1)	Peak Diode Recovery voltage slope	6	V/ns
E _{AS} (2)	Single Pulse Avalanche Energy	558	mJ
T _{stg}	Storage Temperature	-55 to 150	°C
Tj	Max. Operating Junction Temperature	-55 10 150	C
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Note: For the P-CHANNEL MOSFET actual polarity of voltages and current has to be reversed

January 2005

Rev. 2

Table 4: THERMAL DATA

Rthj-pcb	Thermal Resistance Junction-PCB(1 inch ² copper board)*	38	°C/W
Rthj-pcb	Thermal Resistance Junction-PCB (min. footprint)*	100	°C/W
T _I	Maximum Lead Temperature For Soldering Purpose	260	°C

(*) When Mounted on 1 inch² FR-4, 2 Oz copper board

ELECTRICAL CHARACTERISTICS (T_{CASE} = 25 °C UNLESS OTHERWISE SPECIFIED)

Table 5: OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	60			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V_{DS} = Max Rating V_{DS} = Max Rating T _C = 125°C			1 10	μΑ μΑ
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	$V_{GS} = \pm 20V$			±100	nA

Table 6: ON (5)

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$	I _D = 250 μA	2		4	V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V	I _D = 1.25 A		0.18	0.20	Ω

Table 7: DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} ⁽⁵⁾	Forward Transconductance	$V_{DS} = 15 \text{ V}$ $I_D = 1.25 \text{ A}$		1.5		S
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25V f = 1 MHz V_{GS} = 0$		850 230 75		pF pF pF

ELECTRICAL CHARACTERISTICS (continued)

Table 8: SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on Delay Time Rise Time			20 40		ns ns
Q _g Q _{gs} Q _{gd}	Total Gate Charge Gate-Source Charge Gate-Drain Charge	V _{DD} = 48 V I _D = 12 A V _{GS} = 10 V		16 4.0 6.0	21	nC nC nC

Table 9: SWITCHING OFF

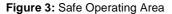
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t _{d(off)} t _f	Turn-off Delay Time Fall Time			40 17		ns ns

Table 10: SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
I _{SD} I _{SDM} ⁽¹⁾	Source-drain Current Source-drain Current (pulsed)					2.5 10	A A
V _{SD} (2)	Forward On Voltage	I _{SD} = 2.5 A	$V_{GS} = 0$			1.2	V
t _{rr} Q _{rr} I _{RRM}	Reverse Recovery Time Reverse Recovery Charge Reverse Recovery Current	$I_{SD} = 12 \text{ A}$ $V_{DD} = 30 \text{ V}$ (see test circu	di/dt = 100A/µs T _j = 150°C it, Figure 5)		100 260 5.2		ns μC Α

(1)Pulse width limited by safe operating area.

 $^{(2)}$ Pulsed: Pulse duration = 300 $\mu s,$ duty cycle 1.5 %.



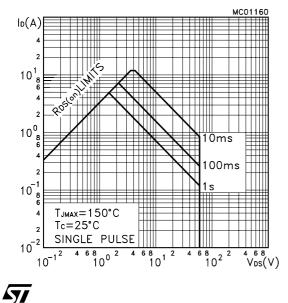
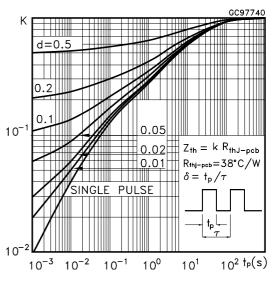


Figure 4: Thermal Impedance



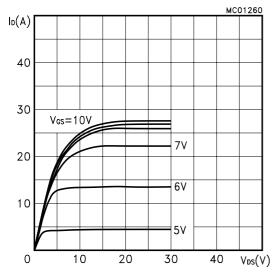


Figure 5: Output Characteristics

Figure 7: Transconductance

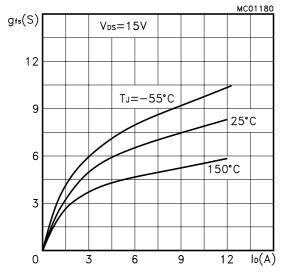


Figure 9: Gate Charge vs Gate-source Voltage

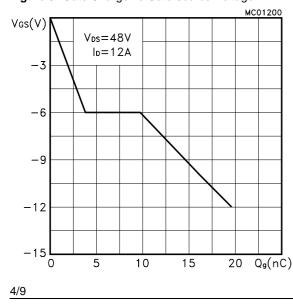


Figure 6: Transfer Characteristics

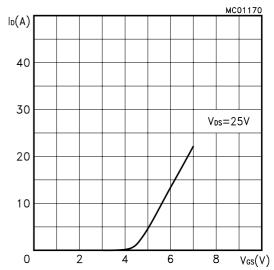


Figure 8: Static Drain-source On Resistance

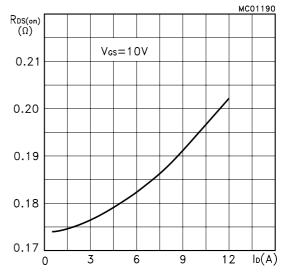
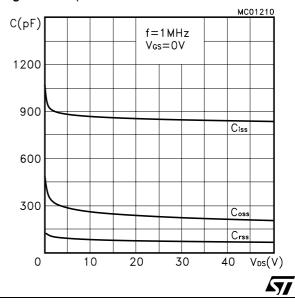


Figure 10: Capacitance Variations



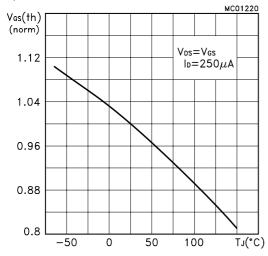
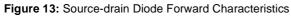


Figure 11: Normalized Gate Threshold Voltage vs Temperature



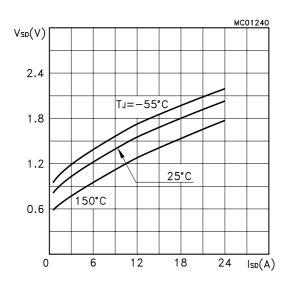
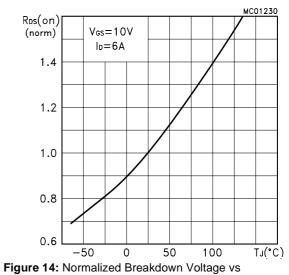
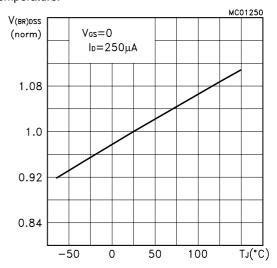


Figure 12: Normalized on Resistance vs Temperature



Temperature.



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Figure 15: Unclamped Inductive Load Test Circuit

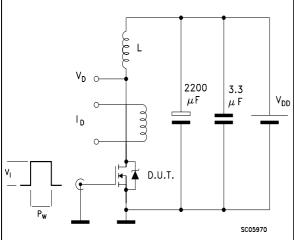


Figure 17: Switching Times Test Circuits For Resistive Load

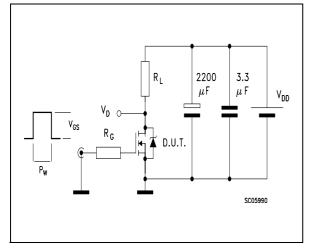
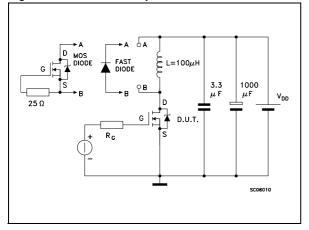


Figure 19: Test Circuit For Inductive Load Switching And Diode Recovery Times



UNCLAMPED I

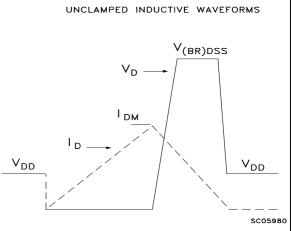
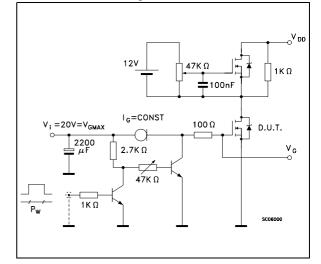


Figure 16: Unclamped Inductive Waveform

Figure 18: Gate Charge test Circuit



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DIM.		mm			inch	
Dim	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
А			1.80			0.071
В	0.60	0.70	0.80	0.024	0.027	0.031
B1	2.90	3.00	3.10	0.114	0.118	0.122
С	0.24	0.26	0.32	0.009	0.010	0.013
D	6.30	6.50	6.70	0.248	0.256	0.264
е		2.30			0.090	
e1		4.60			0.181	
E	3.30	3.50	3.70	0.130	0.138	0.146
Н	6.70	7.00	7.30	0.264	0.276	0.287
V			10 ^o			10 [°]
A1		0.02				



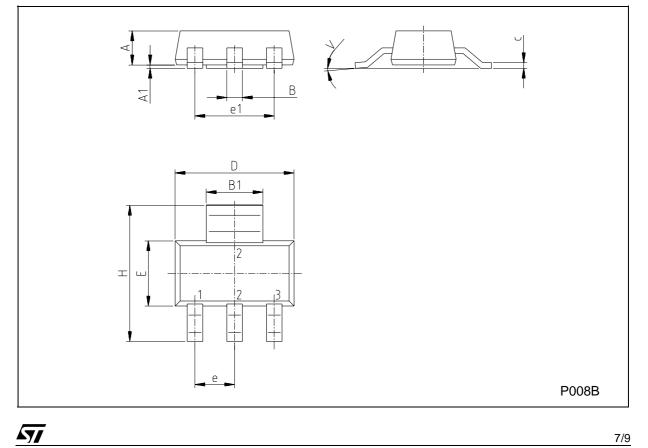


Table 11:Revision History

Date	Revision	Description of Changes
Tuesday 18 January 2005	2.0	ADDED CURVES

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